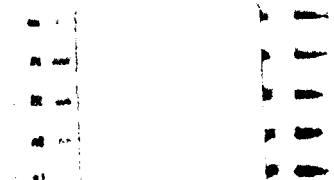
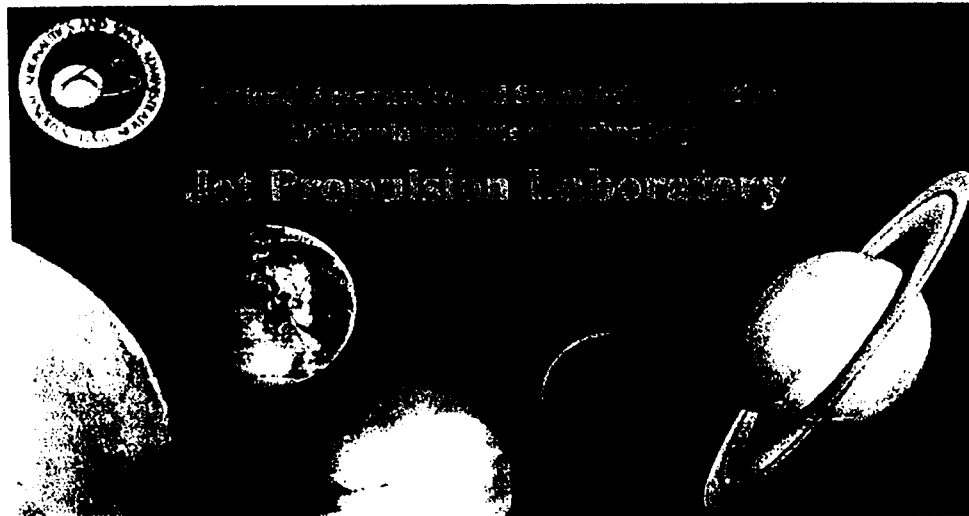


**Microelectronics Reliability & Qualification
Workshop
Pasadena, California
1999**

JPL's Commercial Off-The-Shelf (COTS) Program

**Methods of Infusion of Reliable COTS Plastic
Parts in NASA Flight Hardware**



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Assessment Options for COTS Plastic Parts & Their Relative

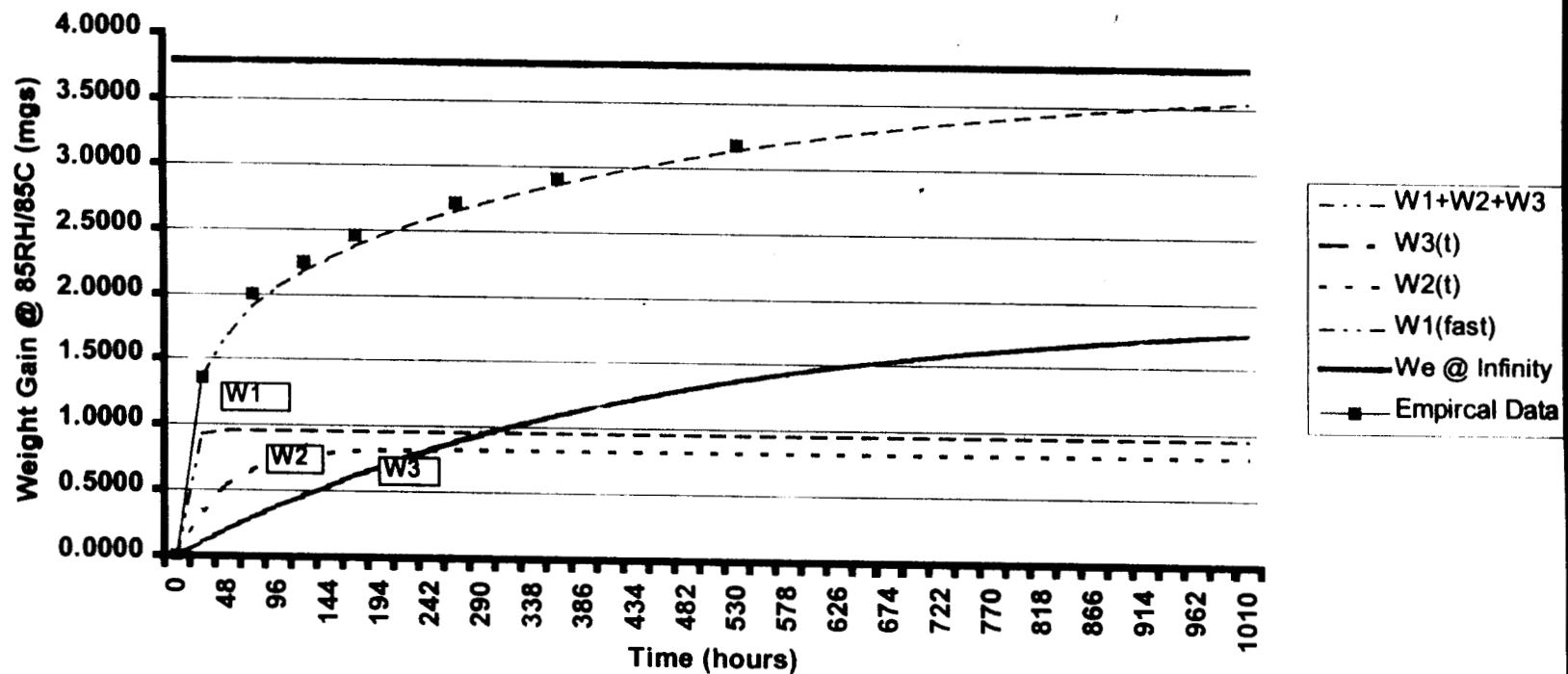
• Temperature/ Humidity	➡	Corrosion	(\$)
• Temperature Cycling	➡	Assembly Defects	(\$\$)
• Moisture Absorption	➡	Popcorning	(\$\$)
• Radiation	➡	TID Degradation	(\$\$\$\$)
• Outgassing	➡	Condensables	(\$)
• Glass Transition	➡	Epoxy Stability	(\$\$)
• Delamination	➡	Voids/Stresses	(\$)
• Upscreening/Burn-in	➡	Performance/Reliability	(\$\$\$\$)
• DPA	➡	Manufacturing Quality	(\$\$)

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Moisture Multiple Absorption Model for SCR265 (Plastic)

$$W(t) = W_e(1 - e^{-kt})$$



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Radiation Results on Plastic Parts

Moisture Absorption / Bake for Intel DA28F016SV in Plastic Package

(0.6 μ m ETOX IV Process Technology)

Conditions: Test Temperature = 25°C, Vdd = 5.0V, Vpp = 5.0V

Dose rate = 25r/s

TID Response of Intel 16M Flash Memory

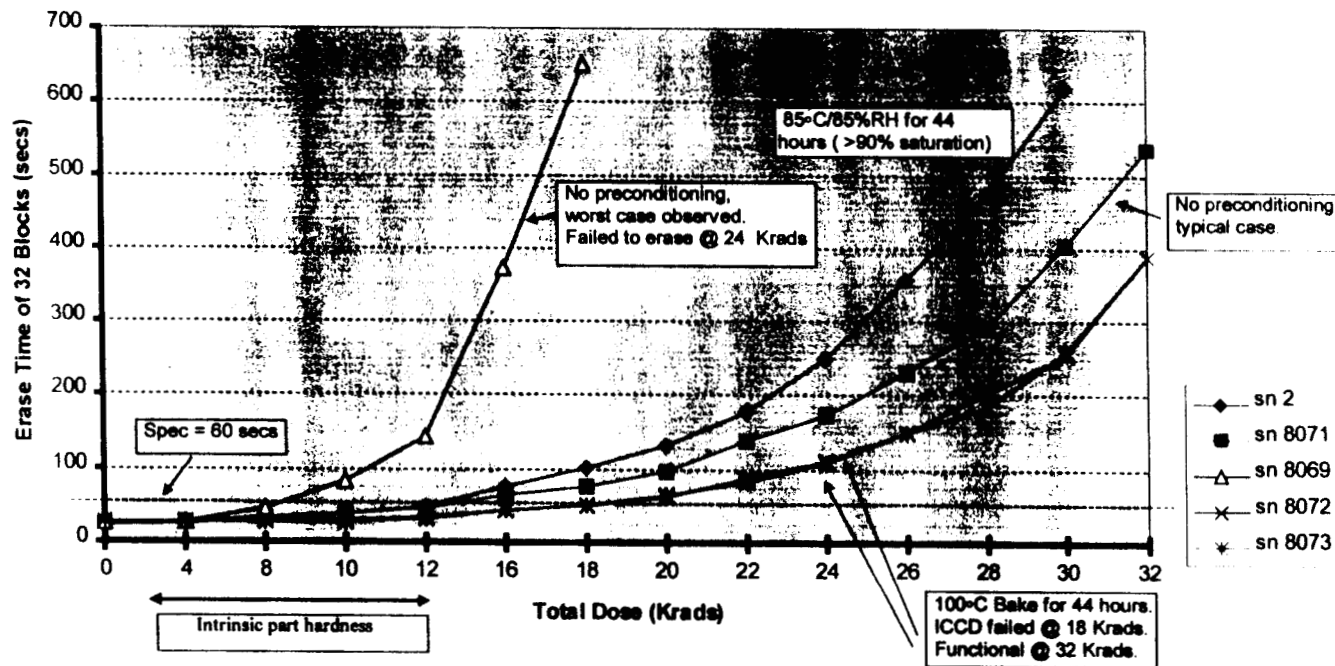
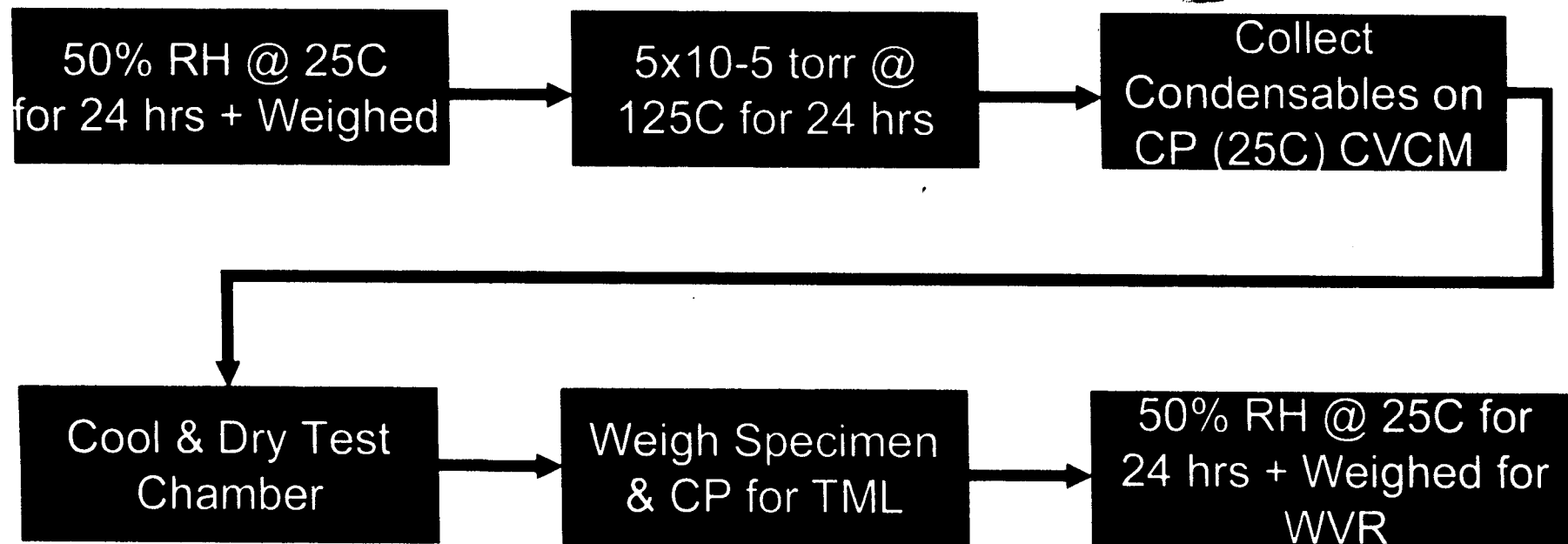


Figure 1
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Outgassing Test Flow for Plastic Packages



Ref: ASTM E595-93

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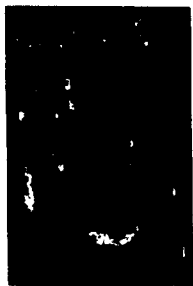
C-SAM Results (No. of Rejects):

Amplifier - Vendor A

Top Side: 0/78⁽¹⁾

Back Side: 3/78

Typical Rejects:



Pass ⁽¹⁾



Fail

ADC - Vendor B

Top Side: 30/78

Back Side: 8/78



Fail



Fail

DC-DC Converter - Vendor C

Top Side: 0/78

Thru Scan: 16/78

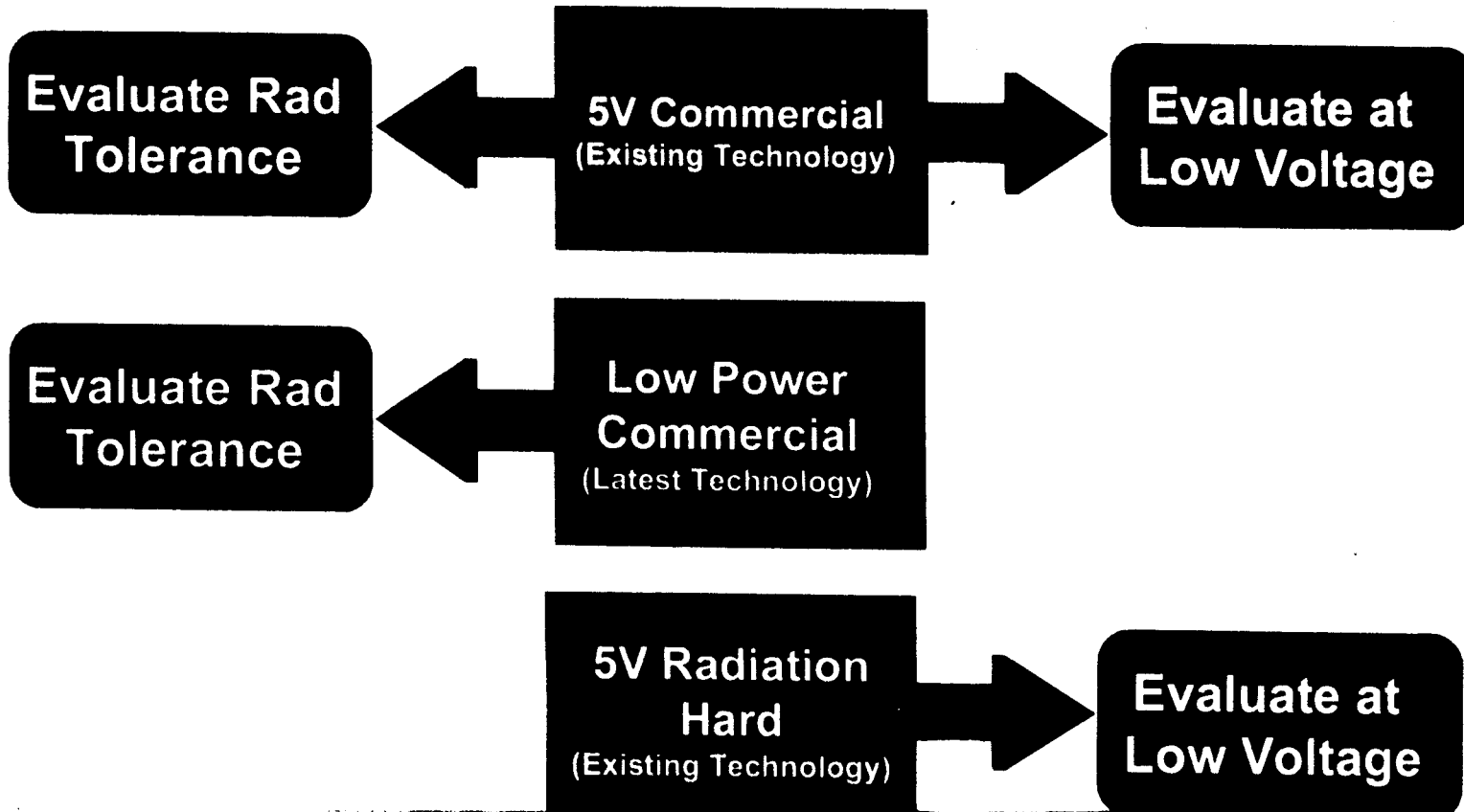


Fail

Note: Units with delamination are defective and were defined by JPL to be a potential risk to mission success. (1) All units showed 100% delamination caused by a special die top coating. These parts were not rejected. F.A. confirmed a die top coating. This was validated by the supplier as a gel coat and is used to relieve stress of the die and improve performance.



Methods to Achieve Low Power Parts:



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IDENTIFY & REVIEW REQUIREMENTS

COST & TAILOR OBJECTIVES

DPA

ELECTRICAL

TEMP CYCLE

C-SAM

ELECTRICAL

Burn-in

ELECTRICAL

**ASSEMBLE
HARDWARE**

**ASSEMBLY
TEST**

**ASSEMBLY
QUALIFICATION**

**FLIGHT
READY**

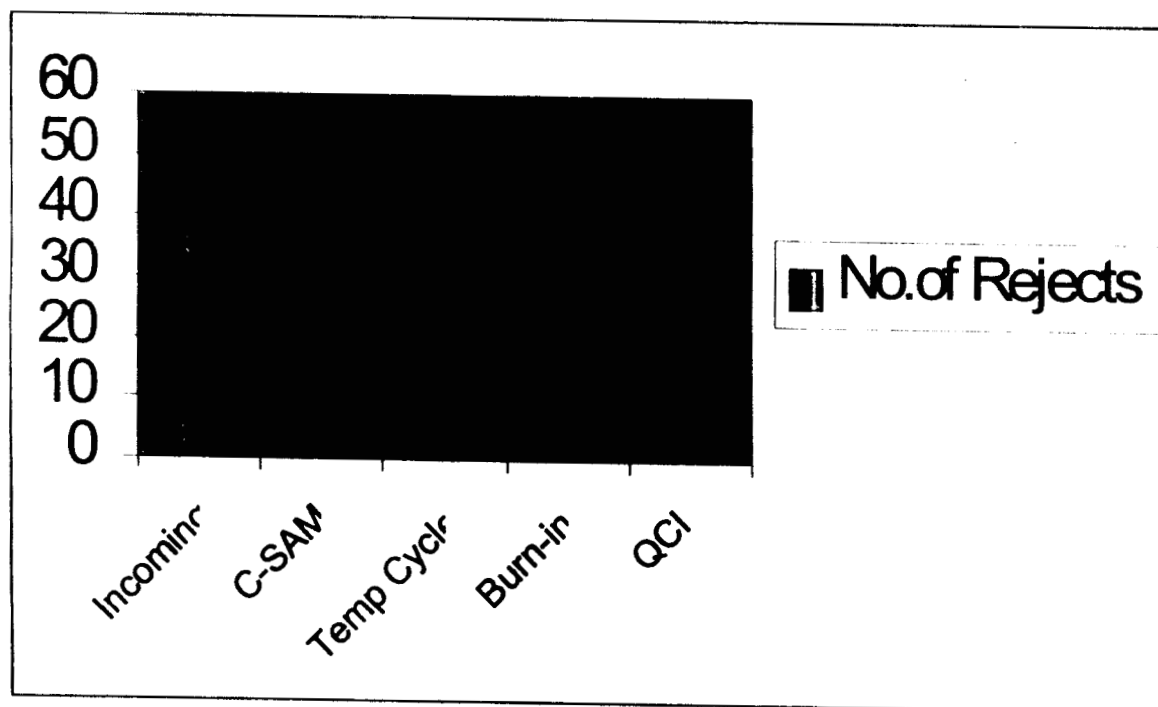
Mini Part Qual (QCI)

COTS⁺⁺ Plastic Infusion Baseline Flow
(Tailored for MARS01 application/mission
requirements)

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COTS++ Upscreening Results



Incoming = 0.42%

C-SAM = 24.35%

Temp Cycle = 5.55%

Burn-in = 1.28%

QCI = 0.00%

Total = 31.60% (3 types)

Total = 24.8% (5 types)

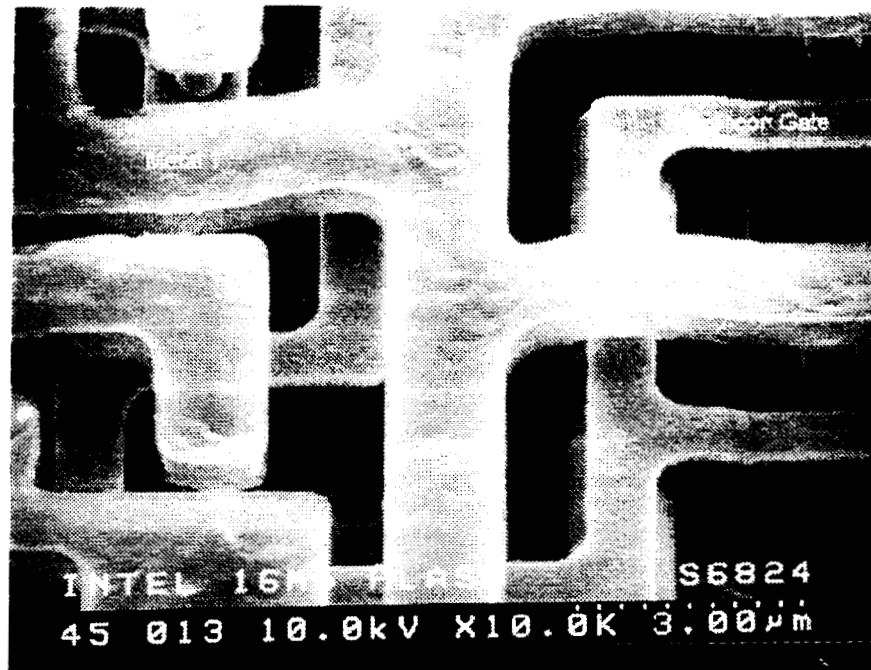


Figure 15. 10kx SEM micrograph showing metallization layer 1 over polysilicon layer 2 gates. Metal layer 1 step coverage was found to be excellent.

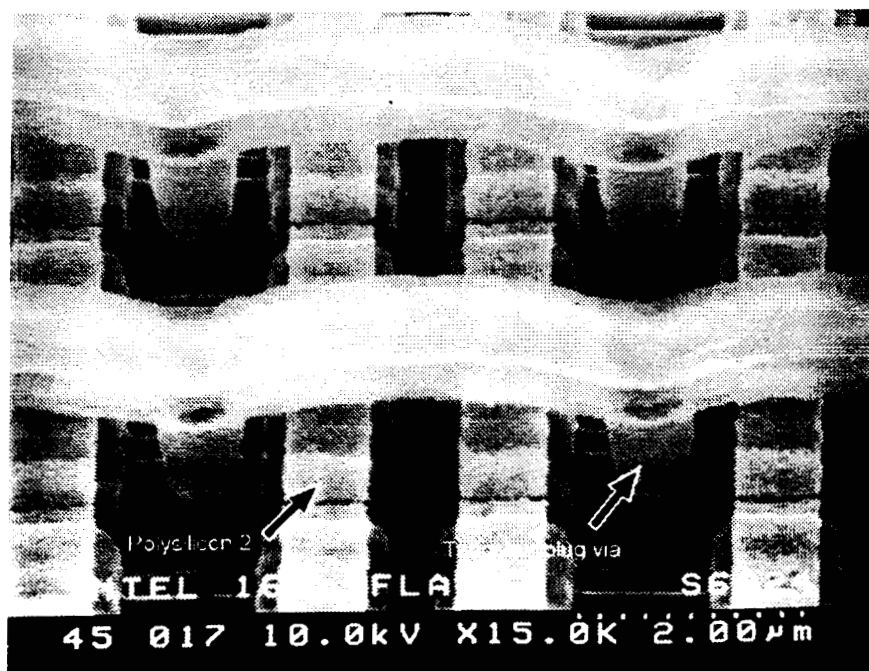


Figure 16. 15kx SEM micrograph closeup of metal layer 1 connections to tungsten plug vias within the memory array. Metal layer 1 is a multilayered structure of aluminum sandwiched between Ti/W layers. Nominal metal 1 thickness was measured to be 0.5 microns.

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Infusion Methods to Insure Low Risk COTS in Critical Space Applications

Guidelines

15 yr mission:

Full Qual/Upscreen

Full Qual/Upscreen

10 yr mission:

Full Qual/Upscreen

Full Qual/Upscreen

5 yr mission:

Full Qual/Upscreen

Full Qual/Upscreen

1 yr mission:

Mini Upscreen/Qual

Mini Upscreen/Qual